


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575093	<b>Applicant(s)/Patent Under Reexamination</b>  MURAKATA ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN structure	8/27/2007	sl
palm inventor (all inventors)	8/27/2007	sl
STN: registry & caplus updated	5-14-2008	sl
PALM all inventors updated	5-14-2008	sl
STN: registry & caplus updated	9-10-2008	sl
PALM all inventors updated	9-10-2008	sl
STN: registry & caplus updated	3-11-2009	sl
PALM all inventors updated	3-11-2009	sl
patentability conference: J. McKane, G. Shameem	3-11-2009	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	363	3-11-2009	sl
548	128	3-11-2009	sl

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